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Christian Morawe
Ali M. Khounsary
Shunji Goto
Editors

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Introduction

This volume contains papers presented at the conference on "Advances in X-Ray/EUV Optics and Components IX", held in San Diego, CA, USA, 18–20 August 2014, as part of the SPIE 2014 International Symposium on Optics + Photonics.

The conference was composed of 9 oral sessions covering the fields Refractive Optics; Multilayers and Gratings; New Developments; Synchrotron Beamlines; Thin Films and Multilayers; Short Pulses; New Materials; Microscopes and Telescopes; and Imaging. It was complemented by a rich poster session.

This conference was focused on technological developments in X-ray/EUV optics for synchrotron and FEL beamlines, laboratory sources, laser and plasma physics, medical imaging, and astronomy. Accordingly, the applications covered a wide spectral range from vacuum ultra violet to hard X-rays. Topics related to metrology, adaptive optics, and computational methods were largely presented in independent conferences belonging to the same program track.

Scheduled for nearly two days of oral presentations accompanied by an evening poster session, this conference was well attended and we would like to thank the authors, speakers, session chairs, program committee members, and the conference participants for their contributions, and the SPIE staff for their help in making it a success.

Christian Morawe
Ali M. Khounsary
Shunji Goto